

MAXIMUM EFFICIENCY

RELIABILITY

Introducing an exciting new initiative
to ensure continued growth and
success for our customers



ENHANCING

RF

TESTING SOLUTIONS

STABILITY

FUTURISTIC

New Directions, New Momentum

STS
Silicon Turnkey Solutions

HIGH PERFORMANCE

Silicon Turnkey Solutions' (STS) technology portfolio has consistently been at the forefront of innovation. With the addition of the **Verigy Port Scale RF Solution**, we are extending the value to our RF customers

The Port Scale RF Solution provides highest test efficiency, minimum cost-of-test, true Quad site and high multi-site parallel efficiency – all integrated into the test head itself. It offers increasing performance, yield enhancement and economic demands without compromising measurement quality or throughput

The New Standard for Testing the Latest 3G, High-integration RF Devices



STS Configuration of Verigy Port Scale RF Solution

- Large Test Head w/DSI
- 192 Channels PS400 @ 200Mbps 32Mv
- "3-2" Port Scale RF 3 Sources
- 24 RF Ports
- MB AV8 4S/4M @ 200Msp
- 2 MSDPS (8 Channels Each)
- Multi-site Software
- Xpress Data Mode

STS Existing Verigy Systems Portfolio

Tester Platform	Digital I/O's	Features
V93000 Pinscale	1024	12.8 GBPS, MB AV8
V93000 Pinscale	768	MB AV8
V93000 Pinscale	576	
V93000 SOC	768	PS 1000, HCDPS, 2 NP Cards
V93000 SOC	768	PS 1000, HCDPS, 2 NP Cards
Port Scale RF	192	24 RF Ports, MB AV8



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For detailed information,
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